
Chipsmall
深圳市津利帝科技有限公司
Geelead Technology Limited
Chipsmall
采购部

International
IOR Rectifier

PD- 93898A

IRF7451

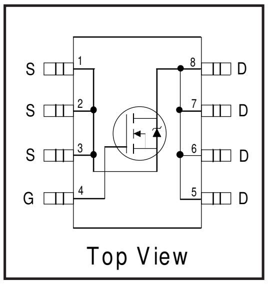
SMPS MOSFET

HEXFET® Power MOSFET

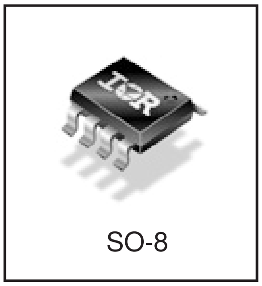
Applications
- High frequency DC-DC converters

V_{DSS}	$R_{DS(on)}$ max	I_D
150V	**0.09Ω**	**3.6A**

Benefits
- Low Gate to Drain Charge to Reduce Switching Losses
- Fully Characterized Capacitance Including Effective C_{OSS} to Simplify Design, (See App. Note AN1001)
- Fully Characterized Avalanche Voltage and Current



Top View



SO-8

Absolute Maximum Ratings

	Parameter	Max.	Units
I_D @ T_A = 25°C	Continuous Drain Current, V_{GS} @ 10V	3.6	A
I_D @ T_A = 70°C	Continuous Drain Current, V_{GS} @ 10V	2.9	
I_{DM}	Pulsed Drain Current ①	29	
P_D @T_A = 25°C	Power Dissipation⑥	2.5	W
	Linear Derating Factor	0.02	W/°C
V_{GS}	Gate-to-Source Voltage	± 30	V
dv/dt	Peak Diode Recovery dv/dt ③	7.9	V/ns
T_J T_{STG}	Operating Junction and Storage Temperature Range	-55 to + 150	°C
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	

Thermal Resistance

Symbol	Parameter	Typ.	Max.	Units
$R_{\theta JL}$	Junction-to-Drain Lead	——	20	°C/W
$R_{\theta JA}$	Junction-to-Ambient ⑥	——	50	

Notes ① through ⑥ are on page 8

Static @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	150	—	—	V	V_{GS} = 0V, I_D = 250μA
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	0.19	—	V/°C	Reference to 25°C, I_D = 1mA ④
$R_{DS(on)}$	Static Drain-to-Source On-Resistance	—	—	0.09	Ω	V_{GS} = 10V, I_D = 2.2A ④
$V_{GS(th)}$	Gate Threshold Voltage	3.0	—	5.5	V	V_{DS} = V_{GS}, I_D = 250μA
I_{DSS}	Drain-to-Source Leakage Current	—	—	25	μA	V_{DS} = 150V, V_{GS} = 0V
		—	—	250		V_{DS} = 120V, V_{GS} = 0V, T_J = 150°C
I_{GSS}	Gate-to-Source Forward Leakage	—	—	100	nA	V_{GS} = 30V
	Gate-to-Source Reverse Leakage	—	—	-100		V_{GS} = -30V

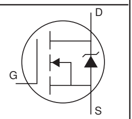
Dynamic @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
g_{fs}	Forward Transconductance	3.5	—	—	S	V_{DS} = 25V, I_D = 2.2A
Q_g	Total Gate Charge	—	28	41	nC	I_D = 2.2A
Q_{gs}	Gate-to-Source Charge	—	6.8	10		V_{DS} = 120V
Q_{gd}	Gate-to-Drain ("Miller") Charge	—	13	20		V_{GS} = 10V ④
$t_{d(on)}$	Turn-On Delay Time	—	10	—	ns	V_{DD} = 75V
t_r	Rise Time	—	4.2	—		I_D = 2.2A
$t_{d(off)}$	Turn-Off Delay Time	—	17	—		R_G = 6.5Ω
t_f	Fall Time	—	15	—		V_{GS} = 10V ④
C_{iss}	Input Capacitance	—	990	—	pF	V_{GS} = 0V
C_{oss}	Output Capacitance	—	220	—		V_{DS} = 25V
C_{rss}	Reverse Transfer Capacitance	—	42	—		ƒ = 1.0MHz
C_{oss}	Output Capacitance	—	1260	—		V_{GS} = 0V, V_{DS} = 1.0V, ƒ = 1.0MHz
C_{oss}	Output Capacitance	—	100	—		V_{GS} = 0V, V_{DS} = 120V, ƒ = 1.0MHz
C_{oss} eff.	Effective Output Capacitance	—	180	—		V_{GS} = 0V, V_{DS} = 0V to 120V ⑤

Avalanche Characteristics

	Parameter	Typ.	Max.	Units
E_{AS}	Single Pulse Avalanche Energy②	—	210	mJ
I_{AR}	Avalanche Current①	—	3.6	A

Diode Characteristics

	Parameter	Min.	Typ.	Max.	Units	Conditions
I_S	Continuous Source Current (Body Diode)	—	—	2.3	A	MOSFET symbol showing the integral reverse p-n junction diode. 
I_{SM}	Pulsed Source Current (Body Diode) ①	—	—	29		
V_{SD}	Diode Forward Voltage	—	—	1.3	V	T_J = 25°C, I_S = 2.2A, V_{GS} = 0V ④
t_{rr}	Reverse Recovery Time	—	76	110	ns	T_J = 25°C, I_F = 2.2A
Q_{rr}	Reverse RecoveryCharge	—	270	400	nC	di/dt = 100A/μs ④

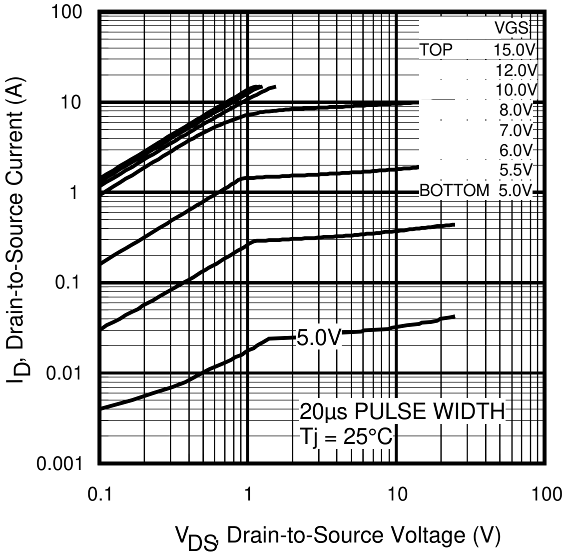


Fig 1. Typical Output Characteristics

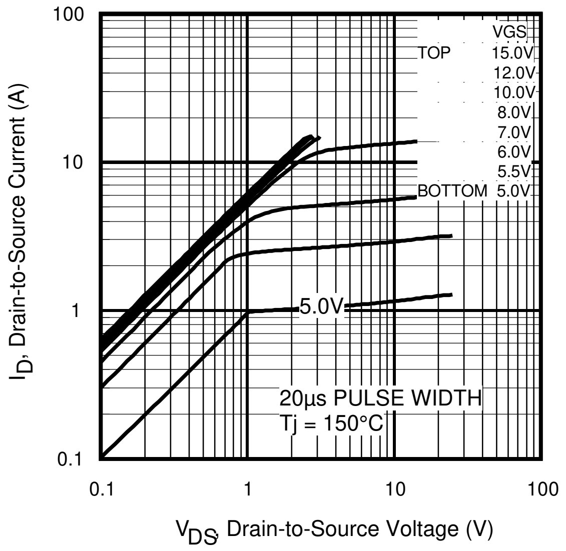


Fig 2. Typical Output Characteristics

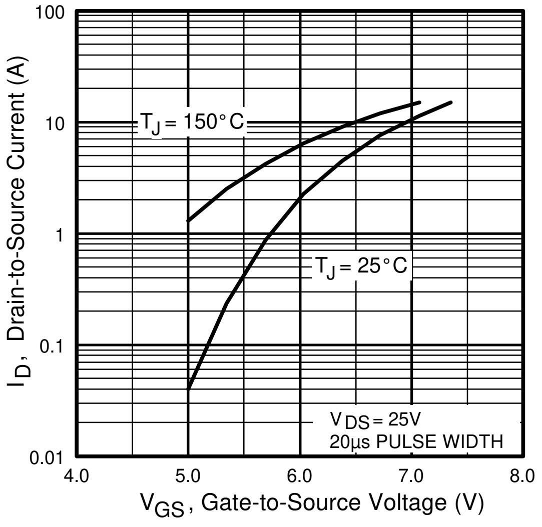


Fig 3. Typical Transfer Characteristics

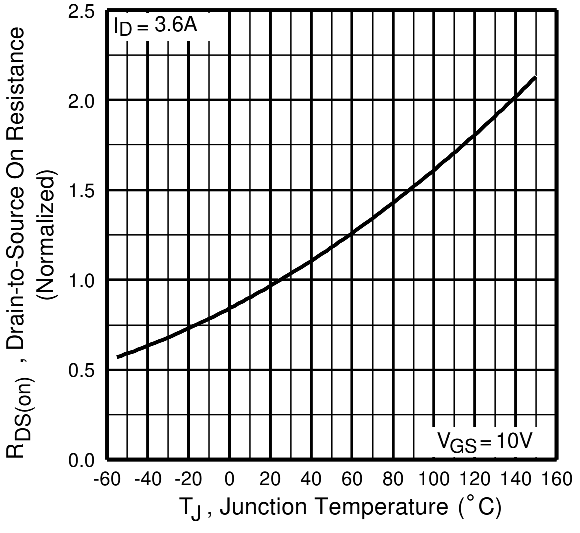


Fig 4. Normalized On-Resistance
Vs. Temperature

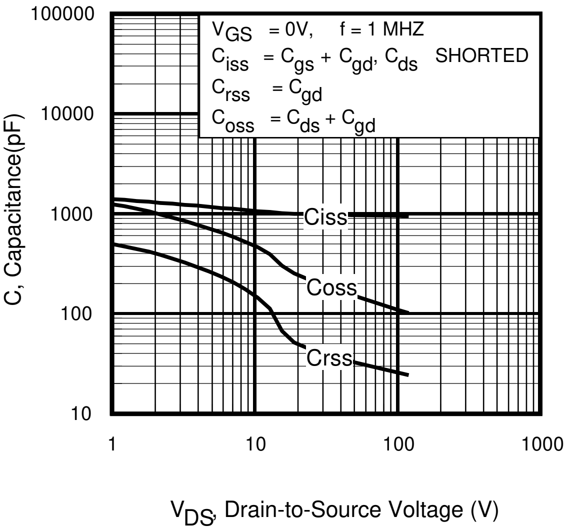


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

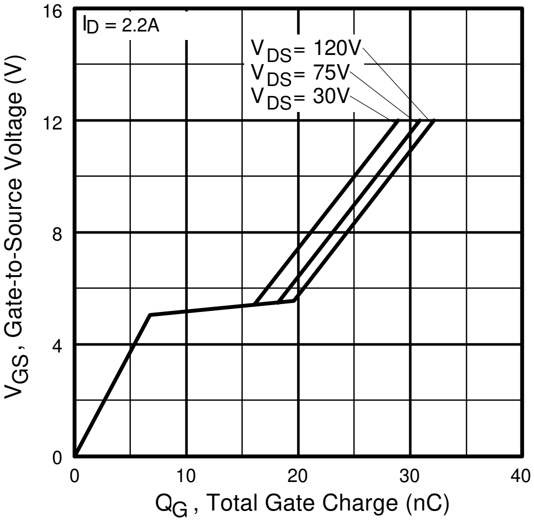


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

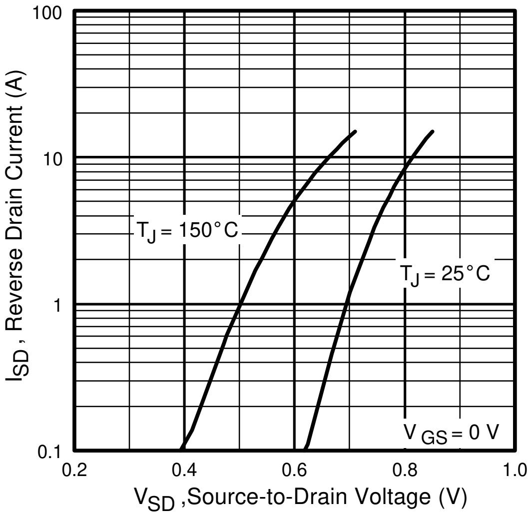


Fig 7. Typical Source-Drain Diode Forward Voltage

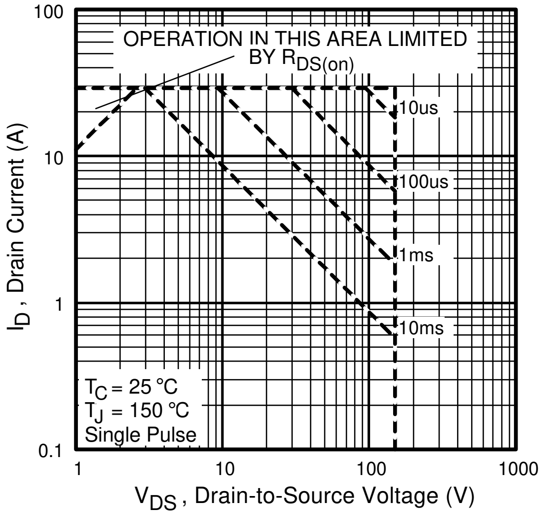


Fig 8. Maximum Safe Operating Area

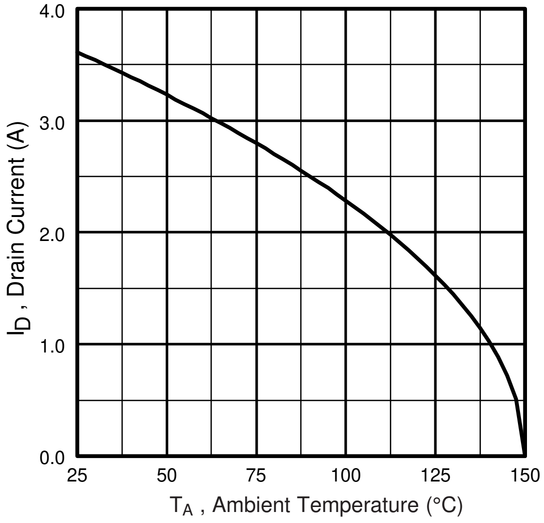


Fig 9. Maximum Drain Current Vs. Ambient Temperature

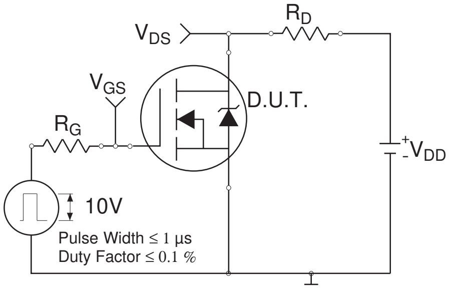


Fig 10a. Switching Time Test Circuit

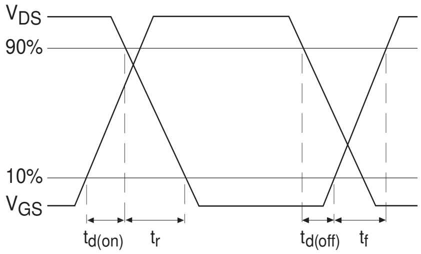


Fig 10b. Switching Time Waveforms

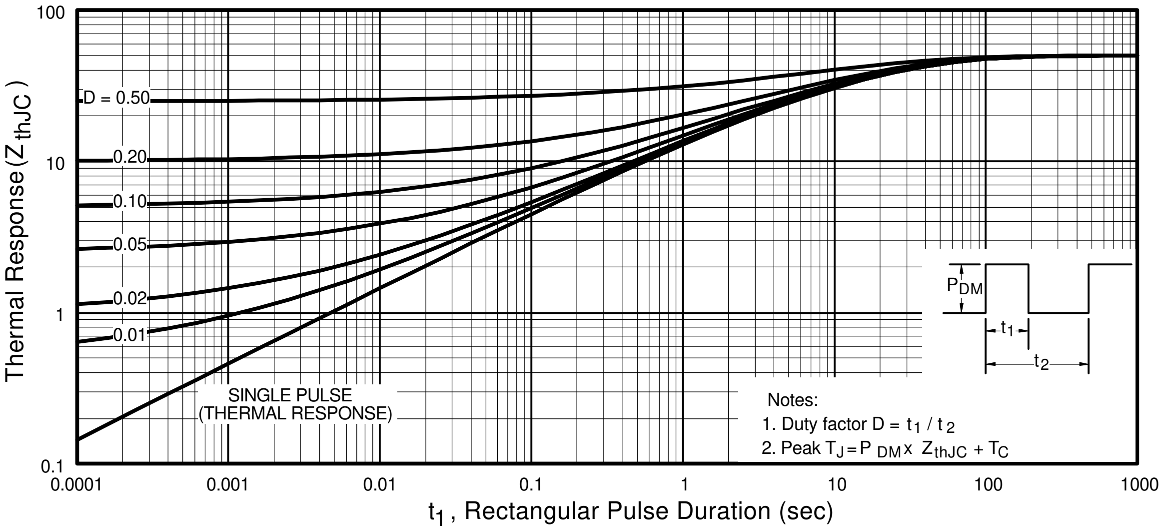


Fig 10. Maximum Effective Transient Thermal Impedance, Junction-to-Case

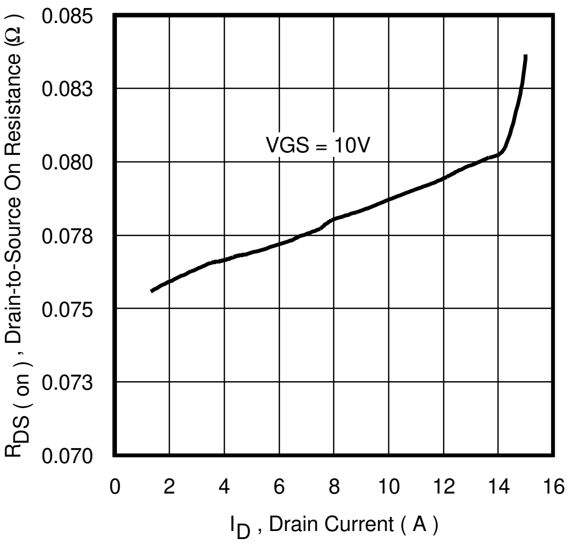


Fig 12. On-Resistance Vs. Drain Current

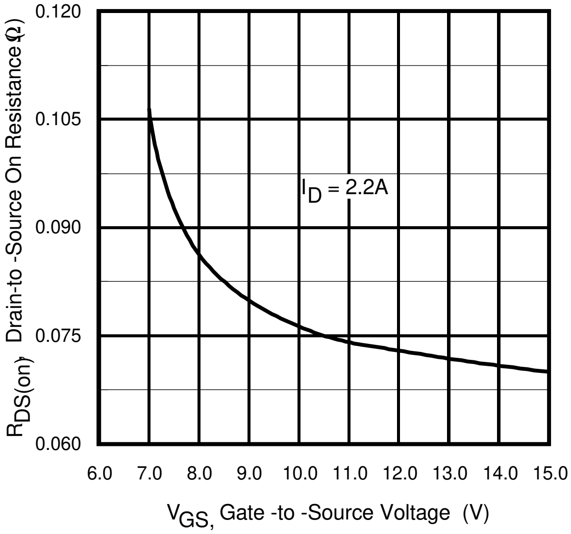


Fig 13. On-Resistance Vs. Gate Voltage

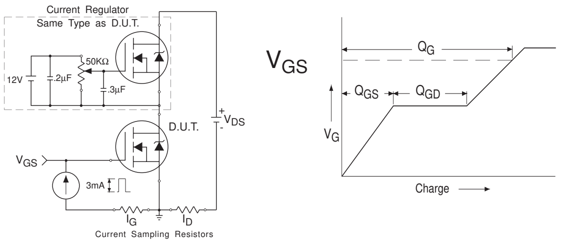


Fig 13a&b. Basic Gate Charge Test Circuit and Waveform

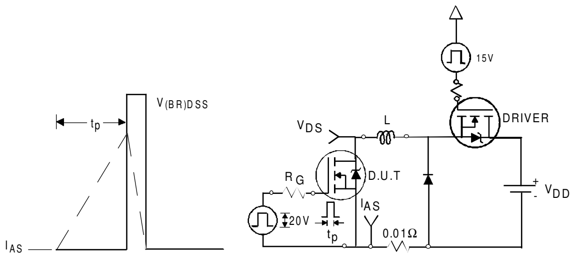


Fig 14a&b. Unclamped Inductive Test circuit and Waveforms

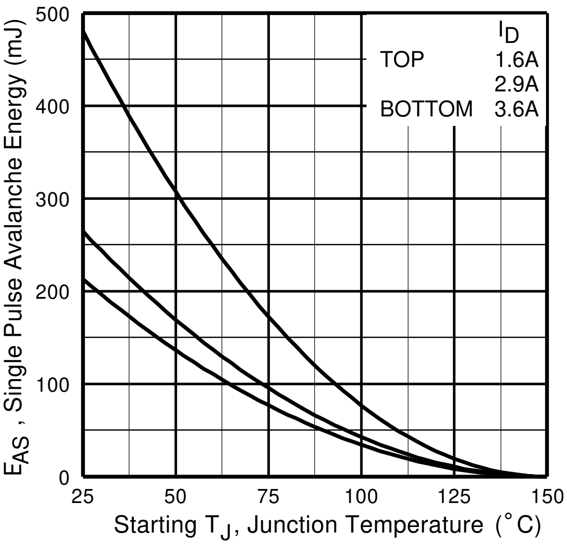
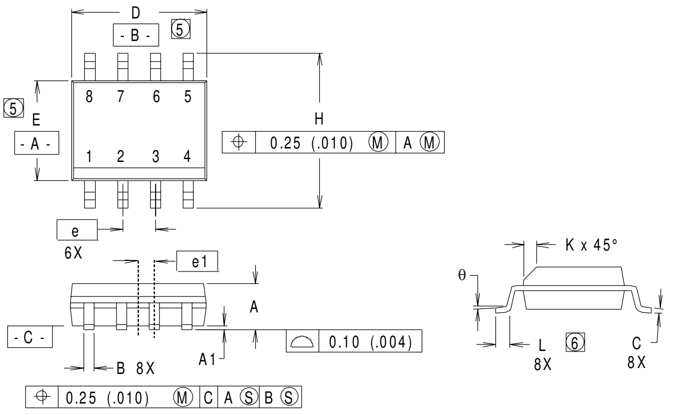


Fig 14c. Maximum Avalanche Energy Vs. Drain Current

SO-8 Package Details



DIM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	.0532	.0688	1.35	1.75
A1	.0040	.0098	0.10	0.25
B	.014	.018	0.36	0.46
C	.0075	.0098	0.19	0.25
D	.189	.196	4.80	4.98
E	.150	.157	3.81	3.99
e	.050 BASIC		1.27 BASIC	
e1	.025 BASIC		0.635 BASIC	
H	.2284	.2440	5.80	6.20
K	.011	.019	0.28	0.48
L	0.16	.050	0.41	1.27
θ	0°	8°	0°	8°

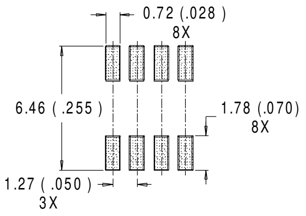
NOTES:

1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M-1982.
2. CONTROLLING DIMENSION : INCH.
3. DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
4. OUTLINE CONFORMS TO JEDEC OUTLINE MS-012AA.

5 DIMENSION DOES NOT INCLUDE MOLD PROTRUSIONS
MOLD PROTRUSIONS NOT TO EXCEED 0.25 (.006).

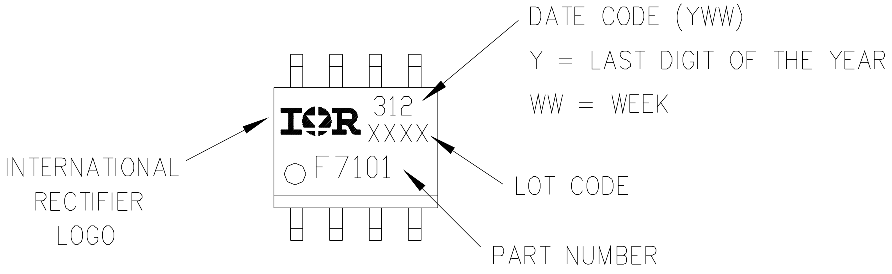
6 DIMENSIONS IS THE LENGTH OF LEAD FOR SOLDERING TO A SUBSTRATE..

RECOMMENDED FOOTPRINT

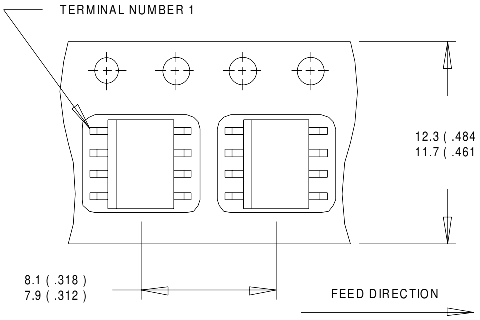


SO-8 Part Marking

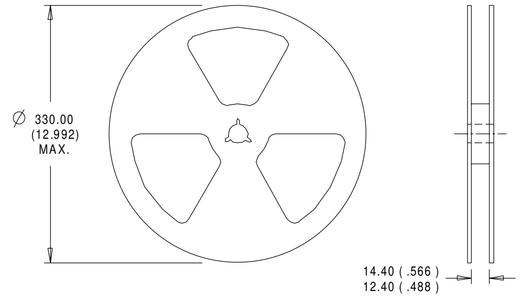
EXAMPLE: THIS IS AN IRF7101



SO-8 Tape and Reel



NOTES:
1. CONTROLLING DIMENSION : MILLIMETER.
2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS(INCHES).
3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



NOTES :
1. CONTROLLING DIMENSION : MILLIMETER.
2. OUTLINE CONFORMS TO EIA-481 & EIA-541.

Notes:

① Repetitive rating; pulse width limited by max. junction temperature.

② Starting $T_J = 25°C$, L = 33mH, $R_G = 25\Omega$, $I_{AS} = 3.6A$.

③ $I_{SD} \leq 2.2A$, $di/dt \leq 180A/\mu s$, $V_{DD} \leq V_{(BR)DSS}$, $T_J \leq 150°C$

④ Pulse width ≤ 400µs; duty cycle ≤ 2%.

⑤ C_{oss} eff. is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}.

⑥ When mounted on 1 inch square copper board.

Data and specifications subject to change without notice.
This product has been designed and qualified for the industrial market.
Qualification Standards can be found on IR's Web site.

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